

**June 2005** 

# ISL9V2540S3S EcoSPARK<sup>TM</sup> N-Channel Ignition IGBT

250mJ, 400V

#### **Features**

- SCIS Energy = 250mJ at T<sub>J</sub> = 25°C
- Logic Level Gate Drive

### **Applications**

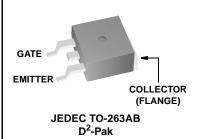
- Automotive Ignition Coil Driver Circuits
- Coil On Plug Applications

#### **General Description**

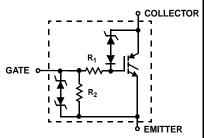
The ISL9V2540S3S is a next generation ignition IGBT that offers outstanding SCIS capability in the industry standard D²-Pak (TO-263) plastic package. This device is intended for use in automotive ignition circuits, specifically as a coil driver. Internal diodes provide voltage clamping without the need for external components.

**EcoSPARK™** devices can be custom made to specific clamp voltages. Contact your nearest Fairchild sales office for more information.

## **Package**



## Symbol



# **Device Maximum Ratings** $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage (I <sub>C</sub> = 1 mA)	430	
BV <sub>ECS</sub>	Emitter to Collector Voltage - Reverse Battery Condition (I <sub>C</sub> = 10 mA)	24	V
E <sub>SCIS25</sub>	At Starting $T_J = 25$ °C, $I_{SCIS} = 12.9$ A, $L = 3.0$ mHy	250 mJ	
E <sub>SCIS150</sub>	At Starting $T_J = 150$ °C, $I_{SCIS} = 10A$ , $L = 3.0$ mHy	150 mJ	
I <sub>C25</sub>	Collector Current Continuous, At T <sub>C</sub> = 25°C, See Fig 9	15.5	Α
I <sub>C110</sub>	Collector Current Continuous, At T <sub>C</sub> = 110°C, See Fig 9	15.3	Α
V <sub>GEM</sub>	Gate to Emitter Voltage Continuous	±10	V
P <sub>D</sub>	Power Dissipation Total T <sub>C</sub> = 25°C	166.7	W
	Power Dissipation Derating T <sub>C</sub> > 25°C	1.11	W/°C
T <sub>J</sub>	Operating Junction Temperature Range	-40 to 175	°C
T <sub>STG</sub>	Storage Junction Temperature Range	-40 to 175	°C
T <sub>L</sub>	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s)	300	°C
T <sub>pkg</sub>	Max Lead Temp for Soldering (Package Body for 10s)	260	°C
ESD	Electrostatic Discharge Voltage at 100pF, 1500Ω (HBM)	4	kV

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
V2540S	ISL9V2540S3ST	TO-263AB	330mm	24mm	800 units
V2540S	ISL9V2540S3S	TO-263AB	Tube	N/A	50 units

# **Electrical Characteristics** $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
ff State	Characteristics						
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage	$I_C = 2mA$ , $V_{GE} = 0$ , $R_G = 1K\Omega$ , See Fig. 15 $T_J = -40$ to 150°C		370	400	430	V
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	$I_C = 10$ mA, $V_{GE} = 0$ , $R_G = 0$ , See Fig. 15 $T_J = -40$ to 150°C		390	420	450	V
BV <sub>ECS</sub>	Emitter to Collector Breakdown Voltage	$I_C = -75 \text{mA}, V_{GE} = 0 \text{V},$ $T_C = 25 ^{\circ}\text{C}$		30	-	-	V
BV <sub>GES</sub>	Gate to Emitter Breakdown Voltage	$I_{GES} = \pm 2mA$		±12	±14	-	V
I <sub>CER</sub>	Collector to Emitter Leakage Current	$V_{CER} = 250V, T_{C} = 25^{\circ}$		-	-	25	μΑ
		$R_G = 1KΩ$ , See Fig. 11	T <sub>C</sub> = 150°C		-	1	mA
I <sub>ECS</sub>	Emitter to Collector Leakage Current	t V <sub>EC</sub> = 24V, See	$T_C = 25^{\circ}C$	-	-	1	mA
		Fig. 11	T <sub>C</sub> = 150°C	-	-	40	mA
R <sub>1</sub>	Series Gate Resistance			-	70	-	Ω
R <sub>2</sub>	Gate to Emitter Resistance			10K	-	26K	Ω

#### **On State Characteristics**

V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	$I_C = 6A,$ $V_{GE} = 4V$	T <sub>C</sub> = 25°C, See Fig. 3	-	1.37	1.8	V
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	$I_C = 10A,$ $V_{GE} = 4.5V$	T <sub>C</sub> = 150°C See Fig. 4	-	1.77	2.2	V

$Q_{G(ON)}$	Gate Charge	I <sub>C</sub> = 10A, V <sub>CE</sub> = 12V, V <sub>GE</sub> = 5V, See Fig. 14	-	15.1	-	nC
V <sub>GE(TH)</sub>	Gate to Emitter Threshold Voltage	$I_C = 1.0 \text{mA},  T_C = 25 ^{\circ}\text{C}$	1.3	-	2.2	V
- ( )		$V_{CE} = V_{GE}$ , See Fig. 10 $T_C = 150^{\circ}C$	0.75	-	1.8	V
$V_{GEP}$	Gate to Emitter Plateau Voltage	I <sub>C</sub> = 10A, V <sub>CE</sub> = 12V	-	3.1	-	V
<del>`</del>	Current Turn-On Delay Time-Resistive	$V_{CF} = 14V, R_1 = 1\Omega$	<u> </u>	0.61		μs
t <sub>riseR</sub>	Current Rise Time-Resistive	$V_{GE} = 14V$ , $N_{C} = 182$ $V_{GE} = 5V$ , $R_{G} = 1K\Omega$ $T_{J} = 25^{\circ}C$	-	2.17	-	μs
t <sub>d(OFF)L</sub>	Current Turn-Off Delay Time-Inductive	$V_{CE} = 300V, L = 500\mu Hy,$	-	3.64	-	μs
	Current Fall Time-Inductive	$V_{GE} = 5V$ , $R_G = 1K\Omega$	-	2.36	-	μs
$t_fL$		$T_J = 25$ °C, See Fig. 12				

## **Typical Performance Curves**

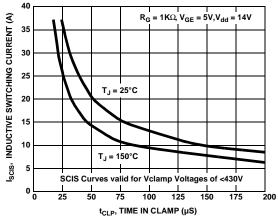


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

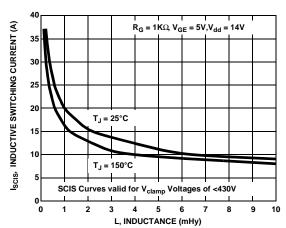


Figure 2. Self Clamped Inductive Switching Current vs Inductance

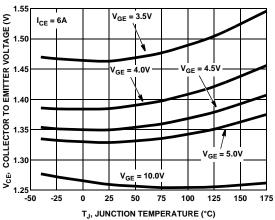


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

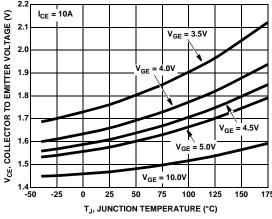


Figure 4. Collector to Emitter On-State Voltage vs Junction Temperature

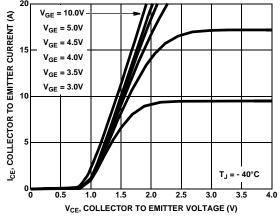


Figure 5. Collector to Emitter On-State Voltage vs Collector Current

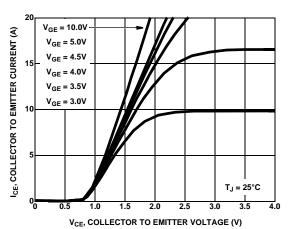


Figure 6. Collector to Emitter On-State Voltage vs Collector Current

# Typical Performance Curves (Continued)

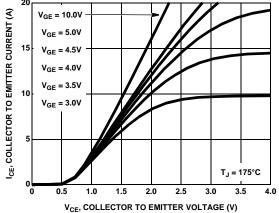


Figure 7. Collector to Emitter On-State Voltage vs Collector Current

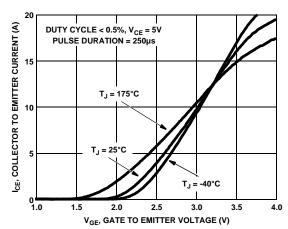


Figure 8. Transfer Characteristics

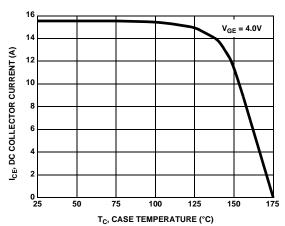


Figure 9. DC Collector Current vs Case Temperature

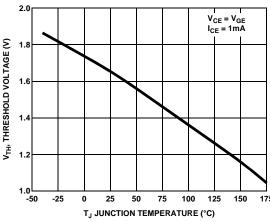


Figure 10. Threshold Voltage vs Junction Temperature

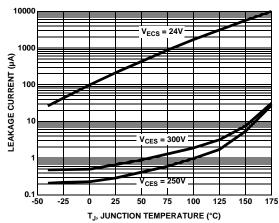


Figure 11. Leakage Current vs Junction Temperature

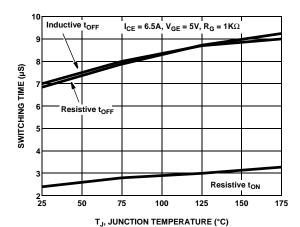


Figure 12. Switching Time vs Junction Temperature

# **Typical Performance Curves (Continued)**

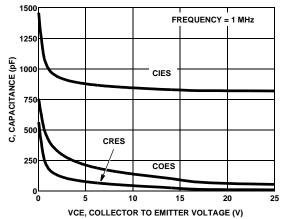


Figure 13. Capacitance vs Collector to Emitter Voltage

Figure 14. Gate Charge

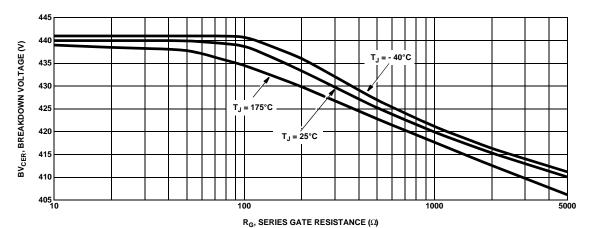


Figure 15. Breakdown Voltage vs Series Gate Resistance

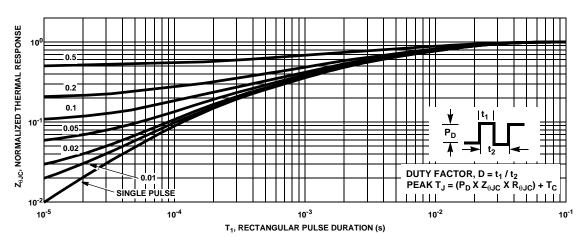
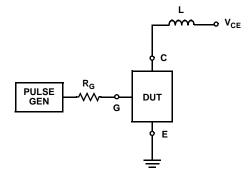


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

## **Test Circuit and Waveforms**



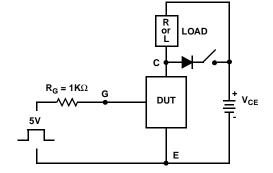
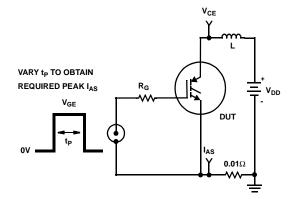


Figure 17. Inductive Switching Test Circuit

Figure 18.  $t_{ON}$  and  $t_{OFF}$  Switching Test Circuit





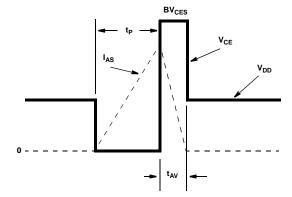
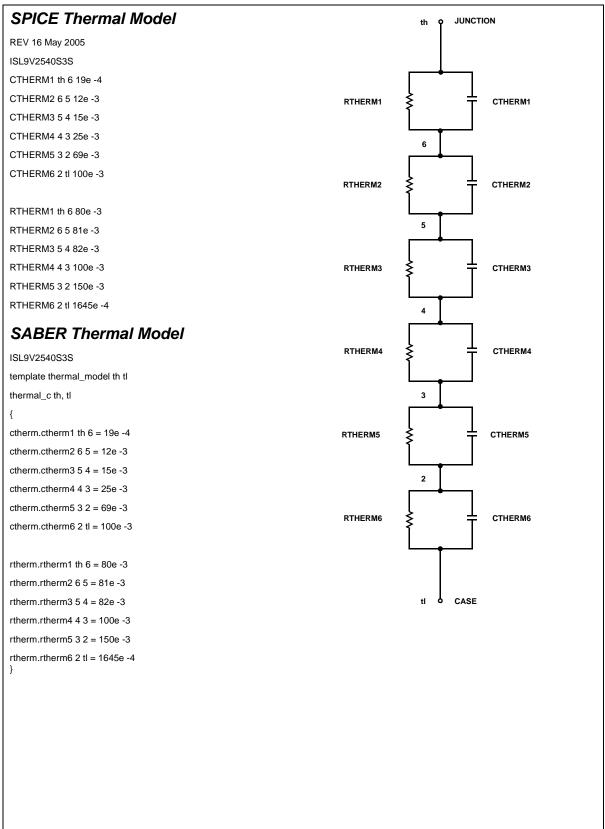


Figure 20. Unclamped Energy Waveforms



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